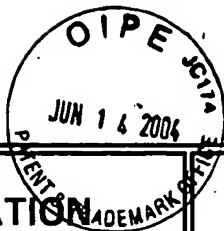


INFORMATION DISCLOSURE CITATION PTO-1449		Customer Number 26615	ATTORNEY'S DKT No. H1107		APPLICATION No. Unassigned	
			APPLICANT(S) Cyrus E. Tabery et al.			
			FILING DATE November 4, 2003		GROUP Unassigned	
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
21	Digh Hisamoto et al., "FinFET-A Self-Aligned Double-Gate MOSFET Scalable to 20 nm," IEEE Transactions on Electron Devices, Vol. 47, No. 12, December 2000, pages 2320-2325.					
	Yang-Kyu Choi et al., "Sub-20nm CMOS FinFET Technologies," 2001 IEEE, IEDM, pages 421-424.					
	Xuejue Huang et al., "Sub-50 nm P-Channel FinFET," IEEE Transactions on Electron Devices, Vol. 48, No. 5, May 2001, pages 880-886.					
	Xuejue Huang et al., "Sub 50-nm FinFET: PMOS," 1999 IEEE, IEDM, pages 67-70.					
	Yang-Kyu Choi et al., "Nanoscale CMOS Spacer FinFET for the Terabit Era," IEEE Electron Device Letters, Vol. 23, No. 1, January 2002, pages 25-27.					
	Copy of U.S. Serial No. 10/348,910; filed January 23, 2003; entitled: "Narrow Fin FinFet," 29 pages.					
2	Copy of U.S. Serial No. 10/614,052; filed July 8, 2003; entitled: "Narrow Fins by Oxidation in Double-Gate FinFet," 18 pages.					
EXAMINER <i>H. P. Carter</i>			DATE CONSIDERED <i>6/23/05</i>			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).



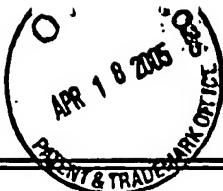
INFORMATION DISCLOSURE CITATION PTO-1449	CUSTOMER NUMBER 26615	ATTORNEY'S DKT No. H1107	APPLICATION No. 10/699,887				
		APPLICANT(S) Cyrus E. TABERY et al.					
		FILING DATE November 4, 2003	GROUP Unassigned				
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
2f	6,709,982	03-2004	Buynoski et al.	438	696		
	6,706,571	03-2004	Yu et al.	438	157		
	6,657,252	12-2003	Fried et al.	257	316		
	6,642,090	11-2003	Fried et al.	438	164		
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	6,657,259	12-2003	Fried et al.	257	350		
	6,583,469	06-2003	Fried et al.	438	151		
	6,630,388	10-2003	Sekigawa et al.	438	396		
	2004/0048424	3-11-04	Wu et al.				
2f	2003/0042531	3-6-03	Lee et al.				
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
2f	Copy of co-pending U.S. Application Serial No. 10/830,006 filed April 23, 2004 entitled: "NARROW FIN FINFET," 15 page specification, 13 sheets of drawings.						
EXAMINER <i>M. P. H. et al.</i>				DATE CONSIDERED <i>6/23/05</i>			

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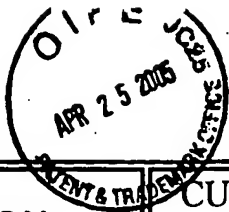
INFORMATION DISCLOSURE CITATION PTO-1449	CUSTOMER NUMBER 26615	ATTORNEY'S DKT No. H1107	APPLICATION No. 10/699,887				
		APPLICANT(S) Cyrus E. TABERY et al.					
		FILING DATE November 4, 2003	GROUP 2822				
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
<i>W</i>	2002/0140039	10/3/02	Ballantine et al.				
	2002/0130354	9/19/02	Ishii et al.				
	6,475,869	11/5/02	Yu				
	6,458,662	10/1/02	Yu				
	6,300,182	10/9/01	Yu				
<i>W</i>	5,757,038	5/26/98	Wind et al.				
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<i>W</i>	EP 1 202 335	5/2/02	Adkisson et al.				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>H. P. ...</i>				DATE CONSIDERED <i>6/28/05</i>			

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INFORMATION DISCLOSURE CITATION PTO-1449		CUSTOMER NUMBER 45114	ATTORNEY'S DKT No. H1107		APPLICATION No. 10/699,887		
			APPLICANT(S) Cyrus E. Tabery et al.				
			FILING DATE November 4, 2003		GROUP 2822		
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
<i>W</i>	6,514,849 B1	02/04/2003	Hui et al.	438	618		
<i>W</i>	6,329,124 B1	12/11/2001	Rangarajan et al.	430	313		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
	International Search Report, PCT/US2004/033251, February 2, 2005, 5 pages.						
	Written Opinion, PCT/US2004/033251, February 2, 2005, 6 pages.						
EXAMINER <i>K.P. Adams</i>				DATE CONSIDERED <i>6/28/05</i>			

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INFORMATION DISCLOSURE CITATION PTO-1449	CUSTOMER NUMBER 45114	ATTORNEY'S DKT No. H1107	APPLICATION No. 10/699,887				
		APPLICANT(S) Cyrus E. Tabery et al.					
		FILING DATE November 4, 2003	GROUP 2822				
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
<i>W</i>	6,855,582 B1	02/15/2005	Dakshina-Murthy et al.	438	157		
<i>W</i>	6,864,164 B1	03/08/2005	Dakshina-Murthy et al.	438	585		
<i>W</i>	6,787,476 B1	09/07/2004	Dakshina-Murthy et al.	438	740		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>W. R. Carr</i>				DATE CONSIDERED <i>6/23/05</i>			

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